

“Insights into the C Distribution in Si:C/Si:C:P and the Annealing Behavior of Si:C Layers”. Dhayalan SK, Nuytten T, Pourtois G, Simoen E, Pezzoli F, Cinquanta E, Bonera E, Loo R, Rosseel E, Hikavy A, Shimura Y, Vandervorst W, ECS journal of solid state science and technology **8**, P209 (2019). <http://doi.org/10.1149/2.0181903JSS>